

Sheet 1 of 1 ATTORNEY DOCKET NO. FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE 1293.1278C4 10/806,318 FIRST NAMED INVENTOR LIST OF REFERENCES CITED BY APPLICANT Yong-jin Ahn et al. FILING DATE GROUP ART UNIT: (Use several sheets if necessary) March 23, 2004 2655 **U.S. PATENT DOCUMENTS** *EXAMINER DOCUMENT SUB-FILING INITIAL NO. **CLASS** DATE DATE CLASS NAME LC ÀÃ 6,396,792 B1 05/2002 **ICHIHARA** AB Lc. 2002/0003762 A1 01/2002 DEKKER AC AD ΑE AF FOREIGN PATENT DOCUMENTS DOCUMENT NO. **ABSTRACT** DATE **COUNTRY TRANSLATION** YES AG JP 03-185628 08/1991 LC Japan X LC AH JP 2000-123367 04/2000 Japan Χ ΑI AJ ΑK AL

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				
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LC	AA	5,291,470	03/1994	Nishiuchi et al.				
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LIST OF COPENDING APPLICATIONS

ATTACHMENT 1(F)						
ATTORNEY DOCKET NO.	APPLICATION NO.					
1293.1278C4	10/806,318					
Yong-jin Ahn et al.						
FILING DATE	GROUP ART UNIT					
March 23, 2004	<u>[</u>					

The following, prior-filed, copending U.S. patent application(s) is/are listed in accordance with the duty of disclosure provisions of 37 CFR § 1.56, so that the Examiner may consider same should he deem any thereof to be material to examination of the subject application. Pursuant to 37 CFR 1.98(a)(2)(iii), a copy of the identified copending application(s) is provided.

It is requested that the Examiner acknowledge his consideration of application(s) below-listed by initialling same in the space provided adjacent each such application and that the Examiner sign and date this form at the bottom thereof to confirm such consideration having been given.

This submission in no way represents an admission that any of the information listed herein constitutes prior art with respect to the subject application and unless and until such prior art status is established, this submission is not a request that the information presented herein be printed on the face of any patent issuing from the subject application in which this information is being filed.

U.S. PATENT APPLICATION DOCUMENTS

*EXAMINER					
INITIAL		U.S. SERIAL NO.	FILING DATE	NAME	ASSIGNEE
LC	1	10/256,244	9/27/02	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
LC	2	10/806,106	3/23/04	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
LC	3	10/806,107	3/23/04	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
Le	4	10/806,320	3/23/04	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
LC	5	10/806,319	3/23/04	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
LC	6	10/806,215	3/23/04	Yong-jin AHN et al.	Samsung Electronics Co., Ltd.
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Sheet 1 of 1 APPLICATION NO. ATTORNEY DOCKET NO. 1293.1278C4 10/806,318 FIRST NAMED INVENTOR Yong-jin Ahn et al.

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

FILING DATE GROUP ART UNIT March 23, 2004 2655

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*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
LC	AA	6,104,685	08/2000	Hideki, et al.			
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
ل	AG	1186297	07/1998	China	X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				
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